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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

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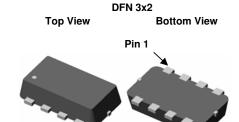


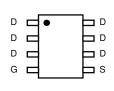


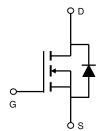


AON4420L

N-Channel Enhancement Mode Field Effect Transistor







Absolute Maximum Ratings T _A =25°C unless otherwise noted								
Parameter		Symbol	Maximum	Units				
Drain-Source Voltage		V_{DS}	30	V				
Gate-Source Voltage		V_{GS}	±20	V				
Pulsed Drain Current ^C		I _{DM}	50					
Continuous Drain	T _A =25°C		10	۸				
Current ^A	T _A =70°C	I _D	8	_ A				
	T _A =25°C	В	1.6	W				
Power Dissipation ^A	T _A =70°C	$-P_{D}$	1	¬				
Junction and Storage Temperature Range		T _J , T _{STG}	-55 to 150	°C				

Thermal Characteristics									
Parameter	Symbol	Тур	Max	Units					
Maximum Junction-to-Ambient A	t ≤ 10s	$R_{\scriptscriptstyle{ hetaJA}}$	34	40	°C/W				
Maximum Junction-to-Ambient A	Steady-State	ГХ⊕ЈА	66	80	°C/W				
Maximum Junction-to-Lead ^B Steady-State		$R_{ heta JL}$	20	25	°C/W				

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Тур	Max	Units			
STATIC PARAMETERS									
BV _{DSS}	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0V$	30			V			
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 30V, V_{GS} = 0V$ $T_{J} = 55^{\circ}C$			1 5	μА			
I _{GSS}	Gate-Body leakage current	$V_{DS} = 0V, V_{GS} = \pm 20V$			±100	nA			
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS} I_{D} = 250 \mu A$	1.4	1.9	2.5	V			
I _{D(ON)}	On state drain current	$V_{GS} = 10V, V_{DS} = 5V$	50			Α			
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} = 10V, I _D = 10A		16	20				
		T _J =125°C		27		mΩ			
		$V_{GS} = 4.5V, I_D = 8A$		21	26				
g FS	Forward Transconductance	$V_{DS} = 5V, I_{D} = 10A$		30		S			
V_{SD}	Diode Forward Voltage	$I_S = 1A, V_{GS} = 0V$		0.75	1	V			
I _S	Maximum Body-Diode Continuous Current				3	Α			
DYNAMIC	PARAMETERS								
C _{iss}	Input Capacitance		440	550	660	pF			
C _{oss}	Output Capacitance	V_{GS} =0V, V_{DS} =15V, f=1MHz	80	110	140	pF			
C _{rss}	Reverse Transfer Capacitance		35	55	80	pF			
R_g	Gate resistance	V_{GS} =0V, V_{DS} =0V, f=1MHz	2	4	6	Ω			
SWITCHII	NG PARAMETERS								
Q _g (10V)	Total Gate Charge (10V)		8	9.8	12	nC			
Q _g (4.5V)	Total Gate Charge (4.5V)	V _{GS} =10V, V _{DS} =15V, I _D =10A	4	4.6	5.5	nC			
Q_{gs}	Gate Source Charge	V _{GS} -10V, V _{DS} -13V, I _D -10A	1.5	1.8	2.2	nC			
Q_{gd}	Gate Drain Charge		1.3	2.2	3	nC			
$t_{D(on)}$	Turn-On DelayTime			5		ns			
t _r	Turn-On Rise Time	V_{GS} =10V, V_{DS} =15V, R_{L} =1.5 Ω ,		3.2		ns			
$t_{D(off)}$	Turn-Off DelayTime	R_{GEN} =3 Ω		24		ns			
t _f	Turn-Off Fall Time			6		ns			
t _{rr}	Body Diode Reverse Recovery Time	I _F =10A, dI/dt=300A/μs	8	11	14	ns			
Q_{rr}	Body Diode Reverse Recovery Charge	I _F =10A, dI/dt=300A/μs	11	13	16	nC			

A: The value of R $_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A = 25°C. The value in any given application depends on the user's specific board design.

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B: Repetitive rating, pulse width limited by junction temperature.

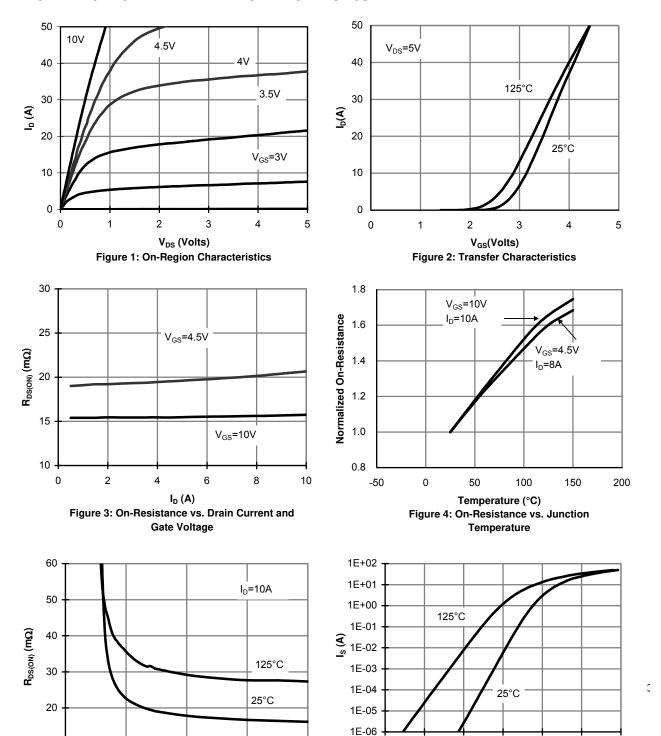
C. The R $_{\theta JA}$ is the sum of the thermal impedence from junction to lead R $_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using $t \le 300 \mu s$ pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C. The SOA curve provides a single pulse rating.

F. The current rating is based on the $t \leqslant 10 s$ thermal resistance rating.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



 $\label{eq:VGS} \mbox{V}_{\mbox{GS}} \mbox{ (Volts)}$ Figure 5: On-Resistance vs. Gate-Source Voltage

6

8

10

4

10

2

1.2

0.6

V_{SD} (Volts)

Figure 6: Body-Diode Characteristics

8.0

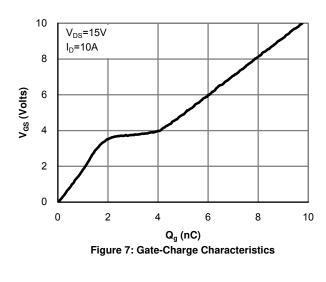
1.0

0.0

0.2

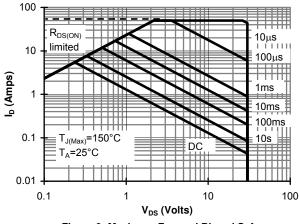
0.4

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



800 Ciss 600 Capacitance (pF) 400 Coss 200 0 0 5 10 15 20 25 30 V_{DS} (Volts)

Figure 8: Capacitance Characteristics



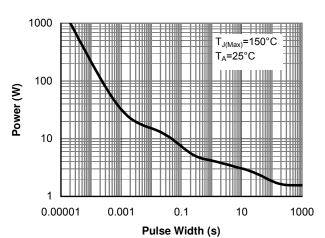


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

Figure 10: Single Pulse Power Rating Junctionto-Ambient (Note E)

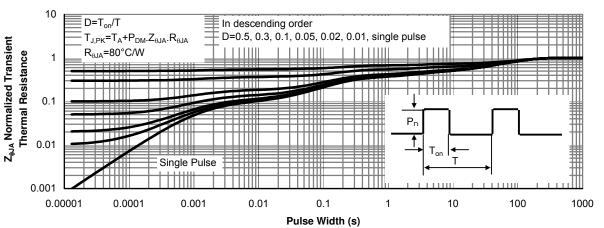
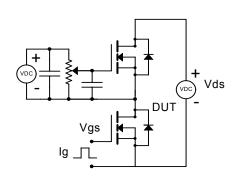
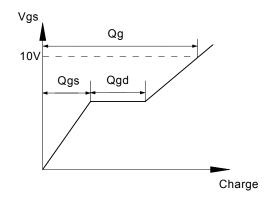


Figure 11: Normalized Maximum Transient Thermal Impedance(Note E)

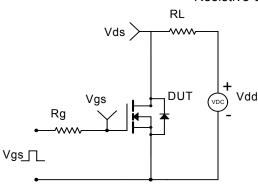
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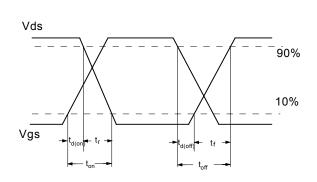
Gate Charge Test Circuit & Waveform





Resistive Switching Test Circuit & Waveforms





Diode Recovery Test Circuit & Waveforms

